

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination OHBA ET AL.	
		Examiner Allen C. Ho	Art Unit 2882	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,432,831	07-1995	Nagai et al.	378/44
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP6347600	12-1994	JAPAN	NAKAYAMA	G21K7/00
	O					
	P					
	Q					
	R					
	S					
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	R. C. Chase and J. K. Silk, "Ellipsoid-hyperboloid x-ray imaging instrument for laser-pellet diagnostics," Applied Optics 14, 2096-2098 (1975).
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	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.